A5G35H120N

Airfast RF Power GaN Transistor

Rev. 0 — December 2021 Data Sheet: Technical Data

This 18 W asymmetrical Doherty RF power GaN transistor is designed for cellular base station applications requiring very wide instantaneous bandwidth capability covering the frequency range of 3300 to 3700 MHz.

This part is characterized and performance is guaranteed for applications operating in the 3300 to 3700 MHz band. There is no guarantee of performance when this part is used in applications designed outside of these frequencies.

3500 MHz

Typical Doherty Single-Carrier W-CDMA Reference Circuit Performance:
 V_{DD} = 48 Vdc, I_{DQA} = 70 mA, V_{GSB} = -4.0 Vdc, P_{out} = 18 W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. (1)

Frequency	G _{ps} (dB)	η _D (%)	Output PAR (dB)	ACPR (dBc)
3400 MHz	16.0	56.6	8.0	-29.8
3500 MHz	15.8	56.7	8.1	-31.3
3600 MHz	15.7	56.2	8.1	-33.1

1. All data measured in reference circuit with device soldered to printed circuit board.

3300-3700 MHz Wideband Performance

Typical Doherty Single- Carrier W- CDMA Reference Circuit Performance:
 V_{DD} = 48 Vdc, I_{DQA} = 70 mA, V_{GSB} = -4.0 Vdc, P_{out} = 18 W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. (1)

Frequency	G _{ps} (dB)	η _D (%)	Output PAR (dB)	ACPR (dBc)
3300 MHz	15.7	54.9	8.1	-29.8
3400 MHz	15.8	56.4	8.0	-29.8
3500 MHz	15.6	56.5	8.2	-31.2
3600 MHz	15.5	56.1	8.1	-33.1
3700 MHz	15.1	50.5	7.6	-32.4

1. All data measured in reference circuit with device soldered to printed circuit board.

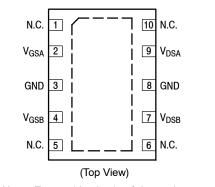
Features

- High terminal impedances for optimal broadband performance
- Improved linearized error vector magnitude with next generation signal
- Able to withstand extremely high output VSWR and broadband operating conditions
- · Designed for low complexity analog or digital linearization systems
- · Optimized for massive MIMO active antenna systems for 5G base stations

A5G35H120N

3300-3700 MHz, 18 W Avg., 48 V AIRFAST RF POWER GaN TRANSISTOR





Note: Exposed backside of the package is the source terminal for the transistor.

Figure 1. Pin Connections



Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	125	Vdc
Gate-Source Voltage	V _{GS}	-8, 0	Vdc
Operating Voltage	V _{DD}	55	Vdc
Maximum Forward Gate Current, I _{G (A+B)} , @ T _C = 25°C	I _{GMAX}	13.3	mA
Storage Temperature Range	T _{stg}	-65 to +150	°C
Case Operating Temperature Range	T _C	-55 to +150	°C
Maximum Channel Temperature	T _{CH}	225	°C

Table 2. Recommended Operating Conditions

Rating	Symbol	Value	Unit
Operating Voltage	V_{DD}	48	Vdc

Table 3. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 115°C, P _D = 15.2 W	R _{θJC} (IR)	2.0 (1)	°C/W
Thermal Resistance by Finite Element Analysis, Channel- to- Case Case Temperature 115°C, P _D = 15.2 W	R _{θCHC} (FEA)	5.8 (2)	°C/W

Table 4. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JS-001-2017)	1B
Charge Device Model (per JS-002-2014)	C3

Table 5. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD22-A113, IPC/JEDEC J-STD-020	3	260	°C

Table 6. Electrical Characteristics (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
Off Characteristics ⁽³⁾		•	•	•	•
(103 1111, 103 1111)	Parrier eaking	_ _	_	2.0 4.4	mAdc
(b) , d) ,	I _{GLK} Carrier eaking	-1.0 -1.0	_ _	_ _	mAdc
n Characteristics — Side A, Carrier					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 4.6 \text{ mAdc})$	V _{GS(th)}	-4.6	-2.4	-1.9	Vdc
Gate Quiescent Voltage (V _{DD} = 48 Vdc, I _{DA} = 70 mAdc, Measured in Functional Test)	V _{GSA(Q)}	-2.75	-2.4	-2.2	Vdc
Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc)	I _{GSS}	-2.0	_	_	mAdc
On Characteristics — Side B, Peaking	·				
Gate Threshold Voltage (V _{DS} = 10 Vdc, I _D = 10 mAdc)	V _{GS(th)}	-4.6	-2.4	-1.9	Vdc
Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc)	I _{GSS}	-4.4	_	_	mAdc

- 1. Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.
- 2. $R_{\theta CHC}$ (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated by the expression MTTF (hours) = $10^{[A + B/(T + 273)]}$, where T is the channel temperature in degrees Celsius, A = -11.6 and B = 9129.

3. Each side of device measured separately. (continued)

A5G35H120N Airfast RF Power GaN Transistor, Rev. 0, December 2021

Data Sheet: Technical Data 2 / 11

Table 6. Electrical Characteristics (T_A = 25°C unless otherwise noted) (continued)

Characteristic	Symbol	Min	Тур	Max	Unit
Functional Tests ⁽¹⁾ (In NXP Doherty Production Test Fixture, 50 ohm sys P _{out} = 16 W Avg., f = 3600 MHz, 1-tone CW. [See note on correct biasin			70 mA, V _{GSB}	$= (V_t - 1.5) V$	dc,

Power Gain	G _{ps}	13.0	14.1	17.5	dB
Drain Efficiency	ηD	40.0	49.1	_	%
Pout @ 6 dB Compression Point	P6dB	48.5	50.7	_	dBm

Wideband Ruggedness $^{(2)}$ (In NXP Doherty Reference Circuit, 50 ohm system) $I_{DQA} = 70$ mA, $V_{GSB} = -4.0$ Vdc, f = 3500 MHz, Additive White Gaussian Noise (AWGN) with 10 dB PAR

(3 dB Input Overdrive from 17.8 W Avg. Modulated Output Power)	ISBW of 400 MHz at 55 Vdc, 35.5 W Avg. Modulated Output Power (3 dB Input Overdrive from 17.8 W Avg. Modulated Output Power)	No Device Degradation
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Typical Performance (2) (In NXP Doherty Reference Circuit, 50 ohm system) $V_{DD} = 48 \text{ Vdc}$, $I_{DQA} = 70 \text{ mA}$, $V_{GSB} = -4.0 \text{ Vdc}$, 3400-3600 MHz Bandwidth

5400-5000 WHZ Dalidwidth					
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW _{res}	_	200	_	MHz
Gain Flatness in 200 MHz Bandwidth @ Pout = 18 W Avg.	G _F	_	0.27	=	dB
Fast CW, 27 ms Sweep					
P _{out} @ 6 dB Compression Point	P6dB	_	100	_	W
AM/PM (Maximum value measured at the P6dB compression point across the 3400–3600 MHz bandwidth)	Φ	_	-15	_	0
Gain Variation over Temperature (-40°C to +85°C)	ΔG	_	0.032	_	dB/°C
Output Power Variation over Temperature (–40°C to +85°C)	ΔP6dB	_	0.002	_	dB/°C

Table 7. Ordering Information

Device	Tape and Reel Information	Package
A5G35H120NT2	T2 Suffix = 2,000 Units, 24 mm Tape Width, 13- inch Reel	DFN 7 × 10

- 1. Part internally input matched.
- 2. All data measured in reference circuit with device soldered to printed circuit board.

NOTE: Correct Biasing Sequence for GaN Depletion Mode Transistors in a Doherty Configuration

Bias ON the device

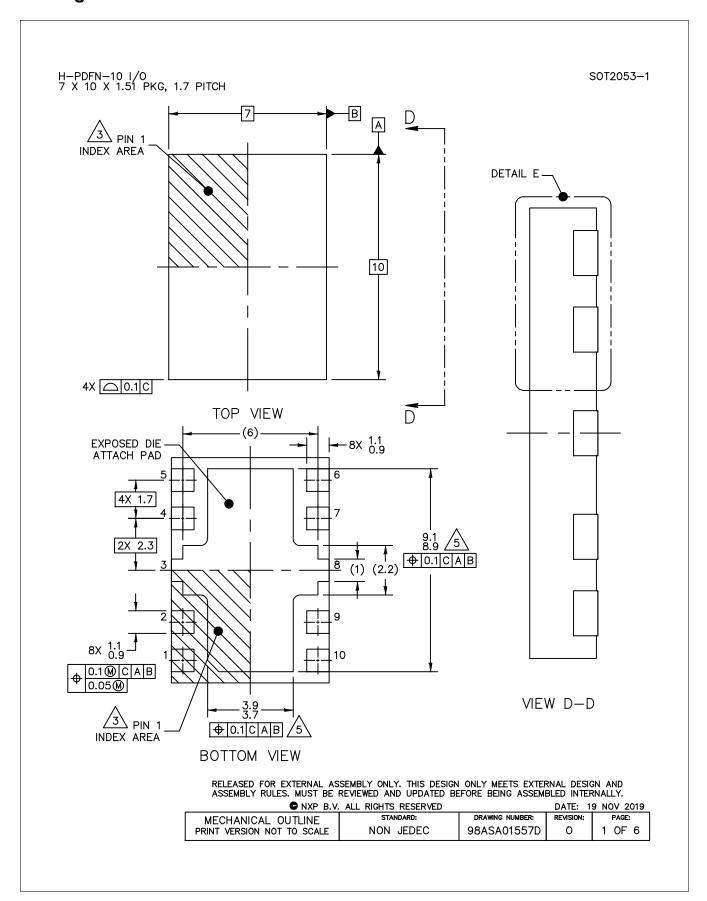
- 1. Set gate voltage V_{GSA} and V_{GSB} to -5~V.
- 2. Set drain voltage $V_{\mbox{\footnotesize DSA}}$ and $V_{\mbox{\footnotesize DSB}}$ to nominal supply voltage (+48 V).
- 3. Increase $V_{\mbox{\footnotesize GSA}}$ (carrier side) until $I_{\mbox{\footnotesize DQA}}$ current is attained.
- 4. Increase V_{GSB} (peaking side) to target bias voltage.
- 5. Apply RF input power to desired level.

Bias OFF the device

- 1. Disable RF input power.
- 2. Adjust gate voltage $V_{\mbox{GSA}}$ and $V_{\mbox{GSB}}$ to –5 V.
- 3. Adjust drain voltage V_{DSA} and V_{DSB} to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Disable V_{GSA} and V_{GSB} .

Data Sheet: Technical Data 3 / 11

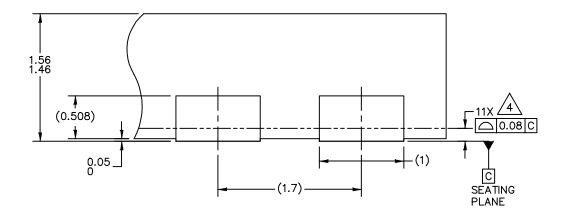
Package Information



Data Sheet: Technical Data 4 / 11

H-PDFN-10 I/O 7 X 10 X 1.51 PKG, 1.7 PITCH

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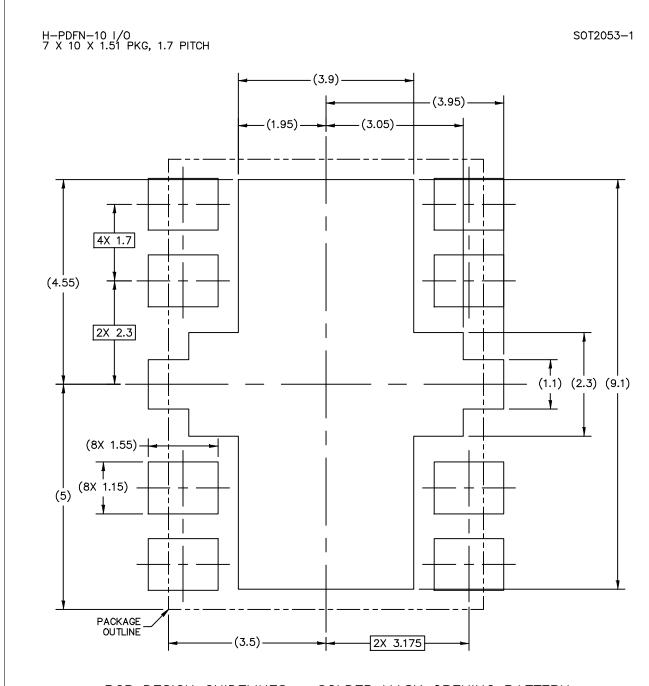


DETAIL E VIEW ROTATED 90°CW

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Data Sheet: Technical Data 5 / 11



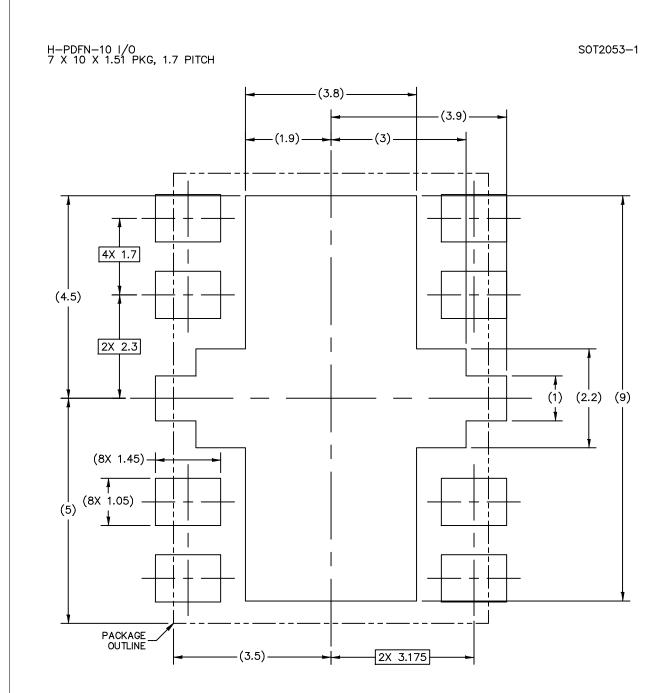
PCB DESIGN GUIDELINES - SOLDER MASK OPENING PATTERN

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6 / 11

Data Sheet: Technical Data



PCB DESIGN GUIDELINES - I/O PADS AND SOLDERABLE AREA

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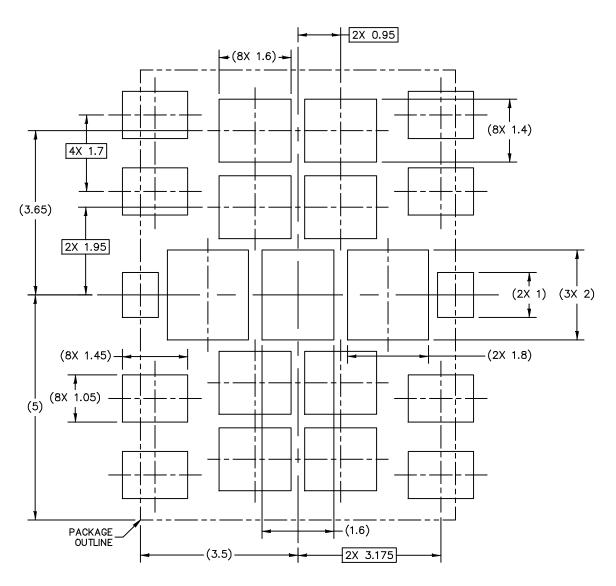
7 / 11

A5G35H120N Airfast RF Power GaN Transistor, Rev. 0, December 2021

H-PDFN-10 I/O 7 X 10 X 1.51 PKG, 1.7 PITCH

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8 / 11



RECOMMENDED STENCIL THICKNESS 0.125 OR 0.15

PCB DESIGN GUIDELINES - SOLDER PASTE STENCIL

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H-PDFN-10 I/O 7 X 10 X 1.51 PKG, 1.7 PITCH

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NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.

COPLANARITY APPLIES TO LEADS AND DIE ATTACH FLAG.

RADIUS ON DIE ATTACH FLAG IS OPTIONAL.

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A5G35H120N Airfast RF Power GaN Transistor, Rev. 0, December 2021 Data Sheet: Technical Data 9 / 11

Product Documentation and Software

Refer to the following resources to aid your design process.

Application Notes

- · AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Software

.s2p File

Revision History

The following table summarizes revisions to this document.

Revision	Date	Description
0	Dec. 2021	Initial release of data sheet

Data Sheet: Technical Data 10 / 11

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Date of release: December 2021 Document identifier: A5G35H120N